PATENT

IN THE UNITED STATES PATENT AND TRADEMARK OFFICE

Applicant:	Bruce et al.	Examiner:	Mohamed, C.
Serial No.:	09/586,518	Group Art Unit:	2857
Filed:	June 2, 2000	Docket No.:	AMDA.455PA
Title:	RESISTIVITY ANALYSIS		

CERTIFICATE UNDER 37 CFR 1.8: The undersigned hereby certifies that this correspondence and the papers, as described hereinabove, are being deposited in the United States Postal Service, as first class mail, in an envelope addressed to: Assistant Commissioner for Patents, Washington, D.C. 20231, on February 7, 2003.

By: E. M. Nichols
Erin M. Nichols

OFFICE ACTION RESPONSE AND AMENDMENT

Assistant Commissioner for Patents
Washington, D.C. 20231

Dear Sir:

In response to the Office Action dated November 18, 2002, please consider the following amendment and remarks.

In the Drawings

Enclosed please find a replacement drawing sheet for Fig. 1 including labels for each box in red ink.

In the Claims

Please replace claims 1, 4 and 21 as indicated below. The changes may be found on the attached sheet.

21. (Amended) A method for analyzing a semiconductor die having suspect circuitry that includes a multitude of circuit paths, the method comprising:

while using a state-changing operation of the suspect circuitry to cause a failure due to the suspect circuitry, identifying one of the circuit paths that electrically changes in response to heat and detecting that a particular circuit portion therein is resistive.